

Factory test results

Serial number: iGp12_0003

August 12, 2010

Table 1: Measured parameters

Parameter	Value
Input -3 dB bandwidth (GHz)	1.42
Input full-scale level (dBm)	1.7
SFDR (dB)	73.7
SINAD (dB)	59.1
ENOB	9.5
Input rise time (ps)	370
Input fall time (ps)	366
Input overshoot (%)	26.8
Input undershoot (%)	26.8
Output rise time (ps)	332
Output fall time (ps)	342
Output amplitude (mVpp)	656
Output overshoot (%)	14.6
Output undershoot (%)	10.9
Group delay (ns)	248.4

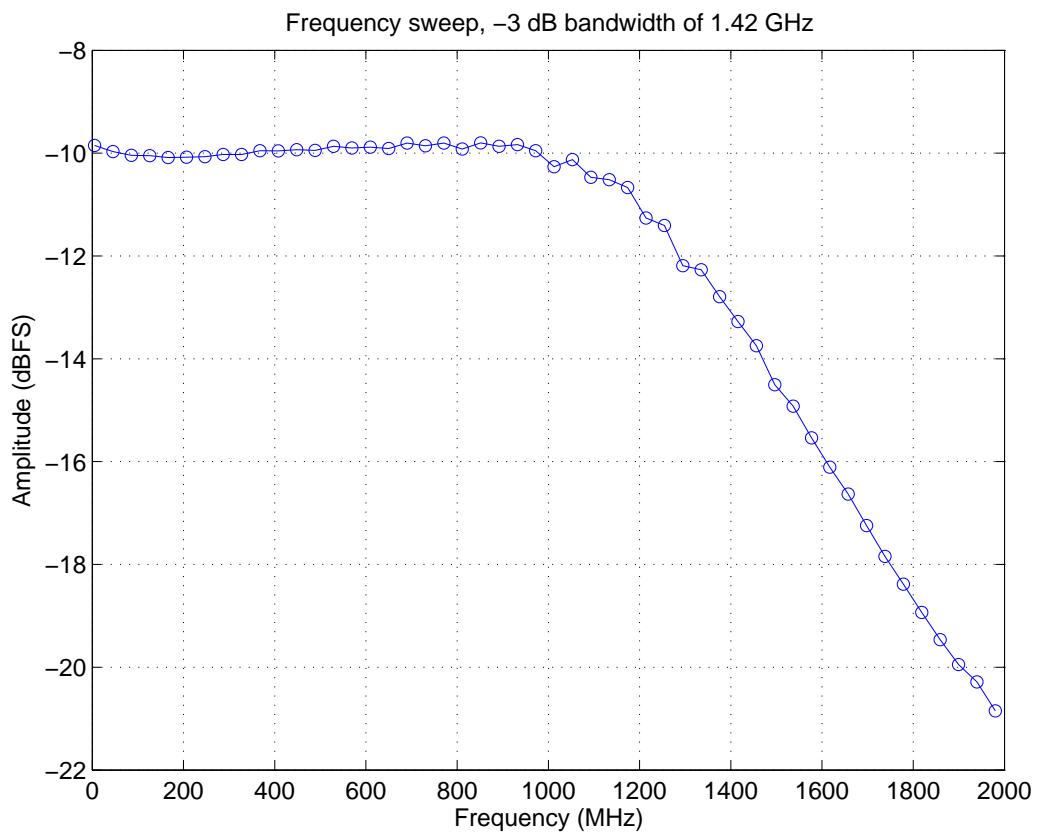


Figure 1: ADC frequency response

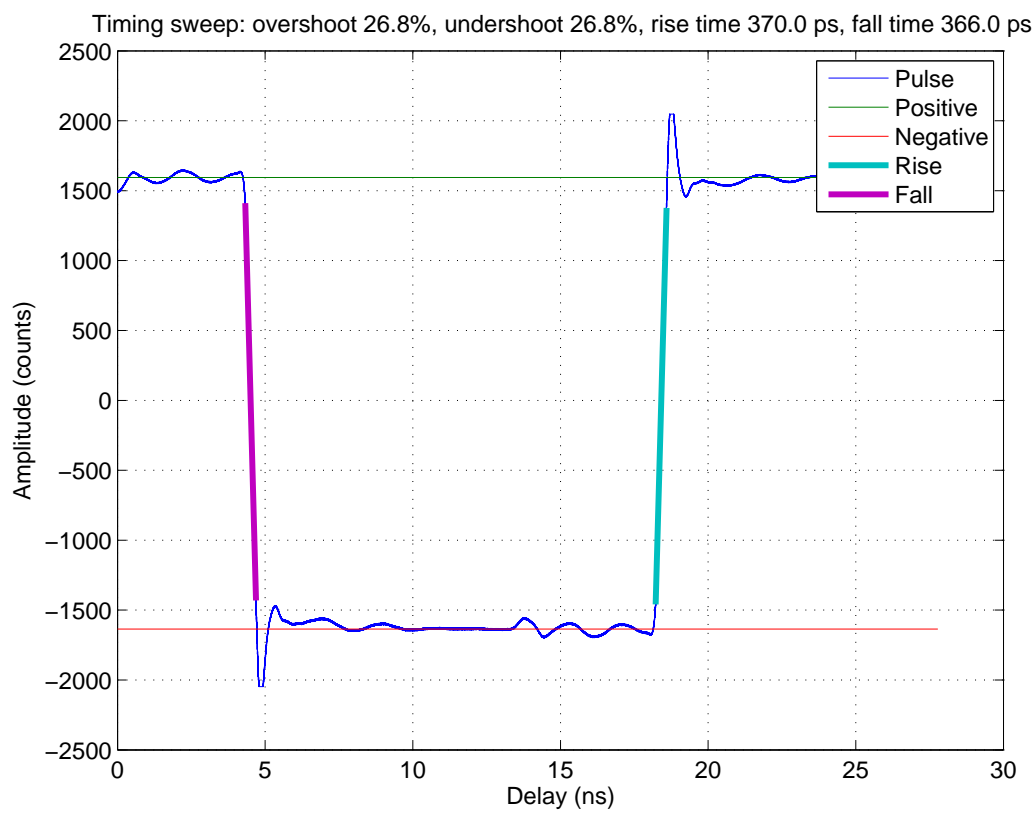


Figure 2: ADC step response

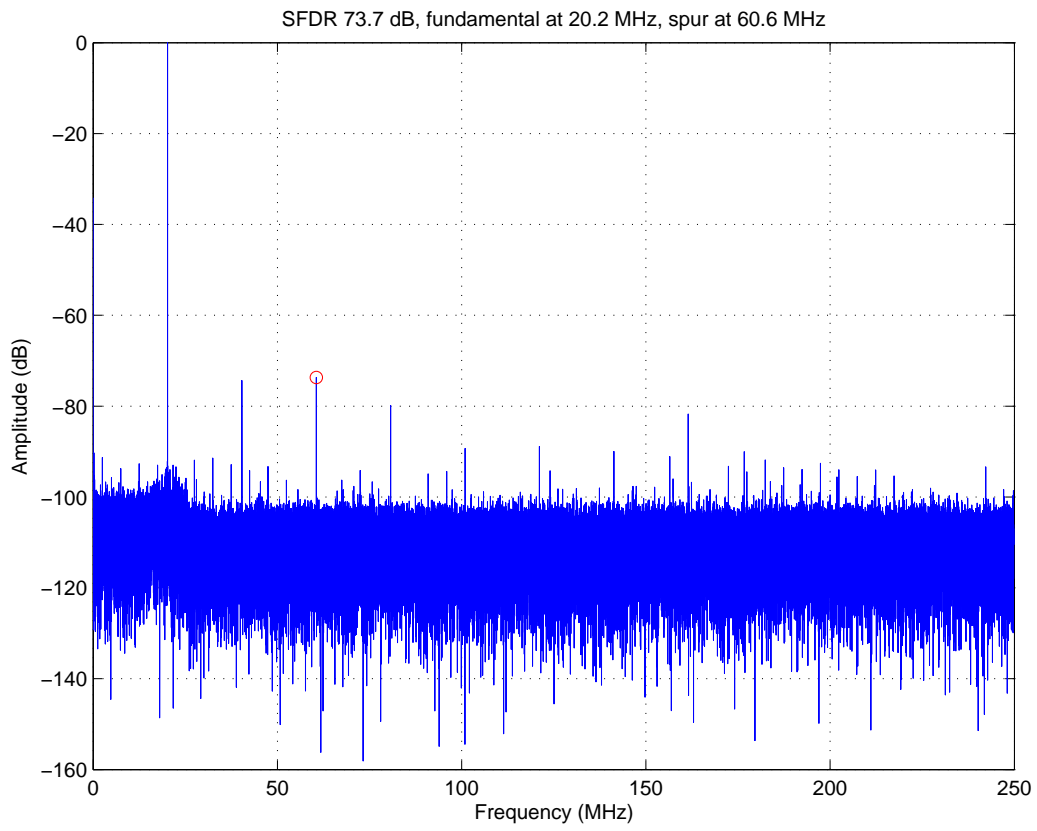


Figure 3: Spurious-free dynamic range

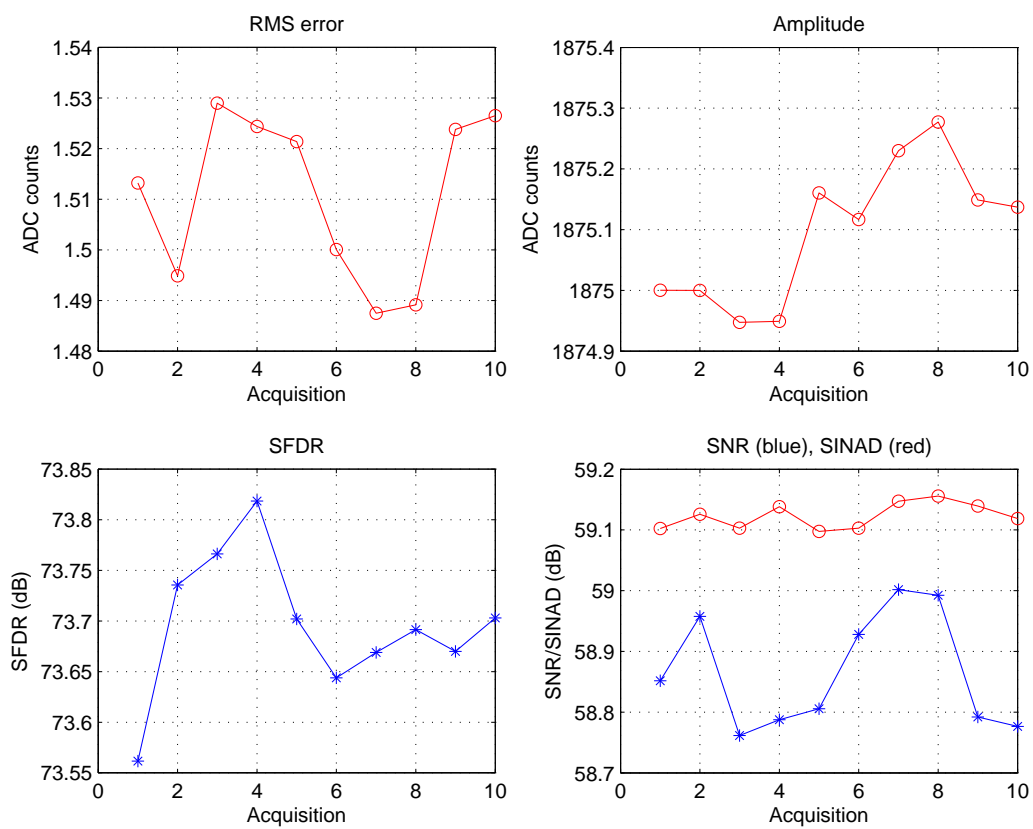


Figure 4: ADC tests: SNR, SFDR, SINAD, RMS error

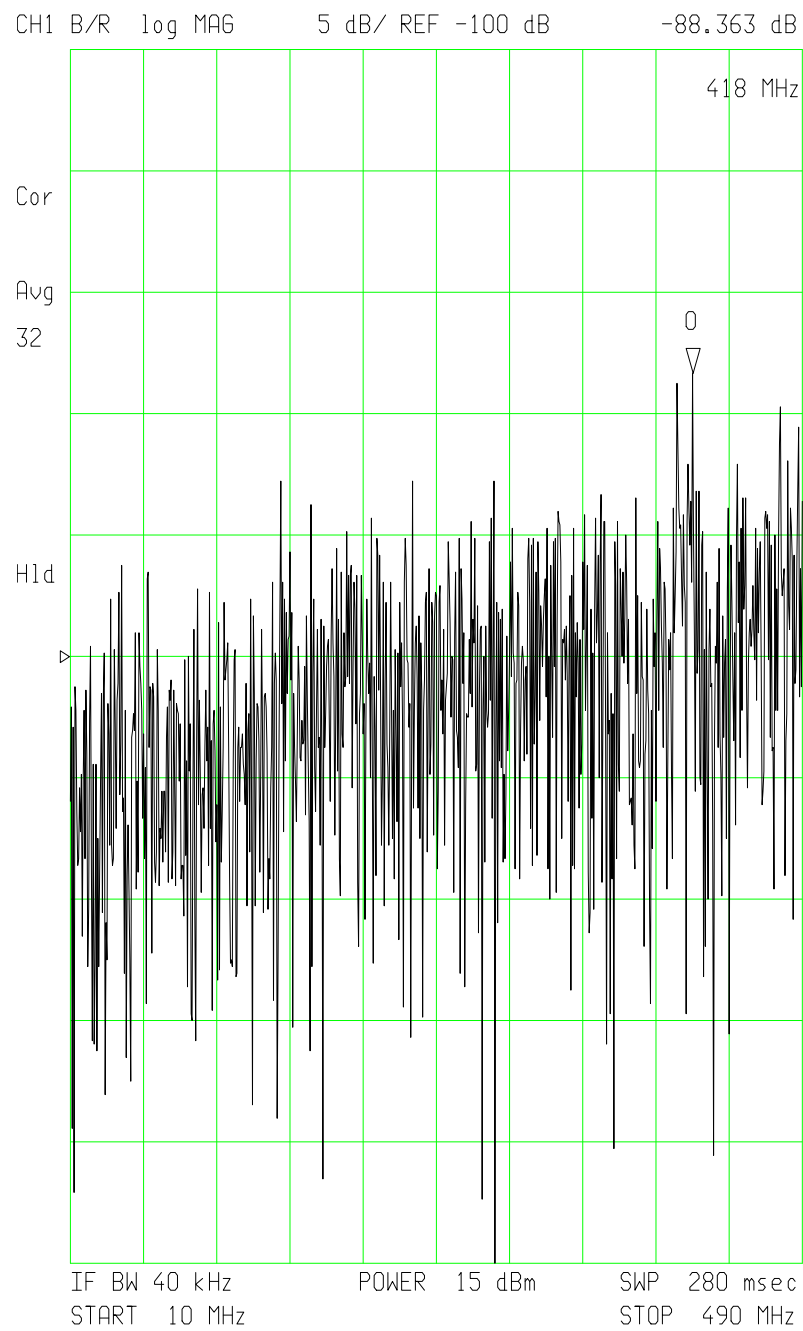


Figure 5: ADC to DAC coupling (feedback off)

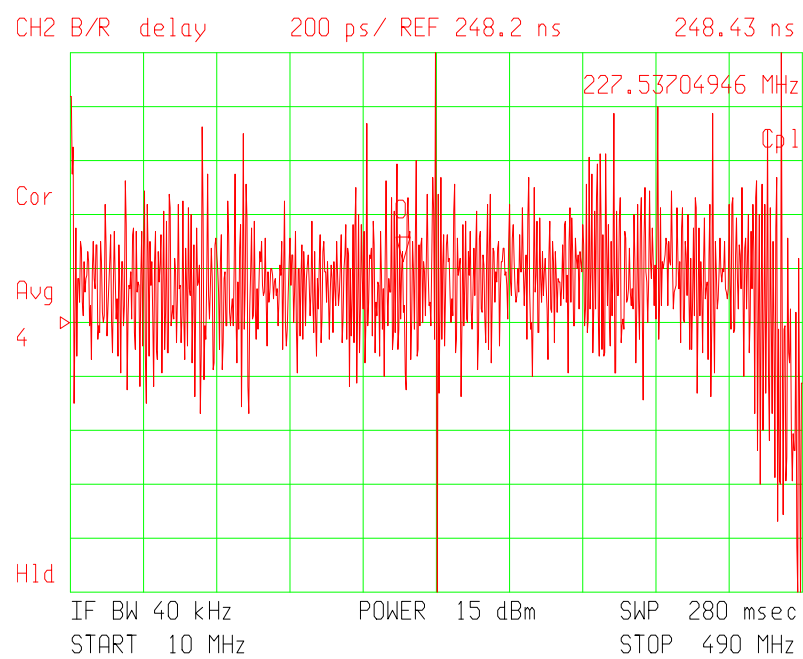
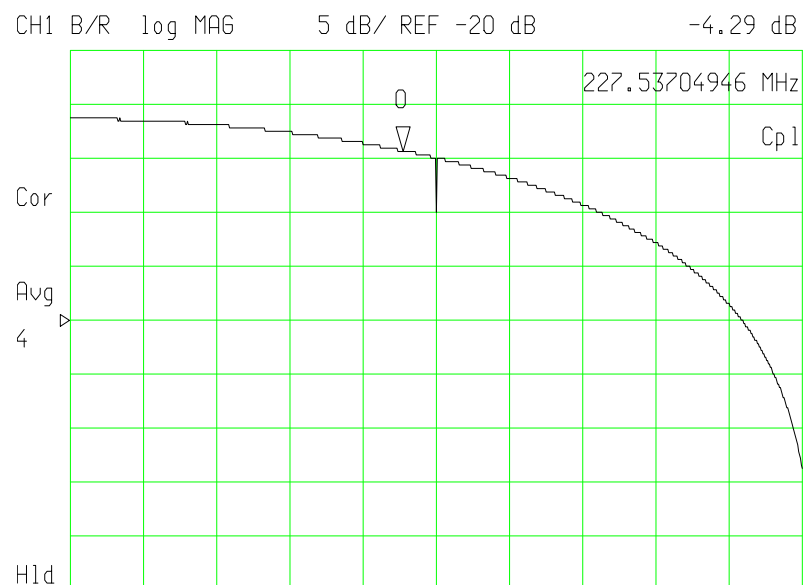


Figure 6: Through mode

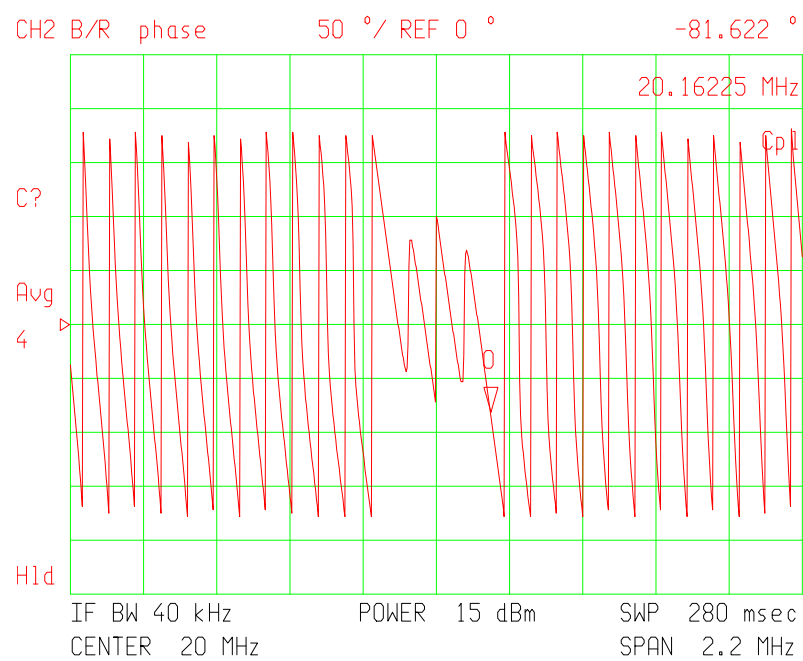
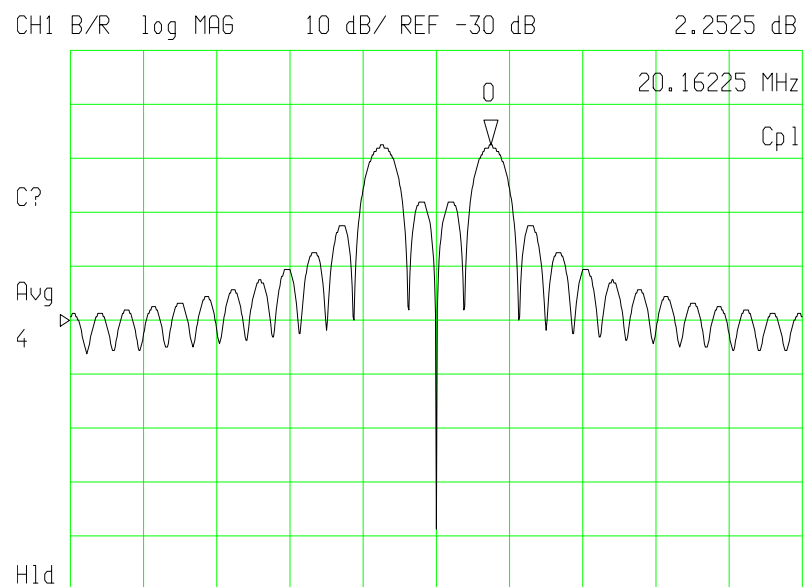


Figure 7: Filter, no downsampling

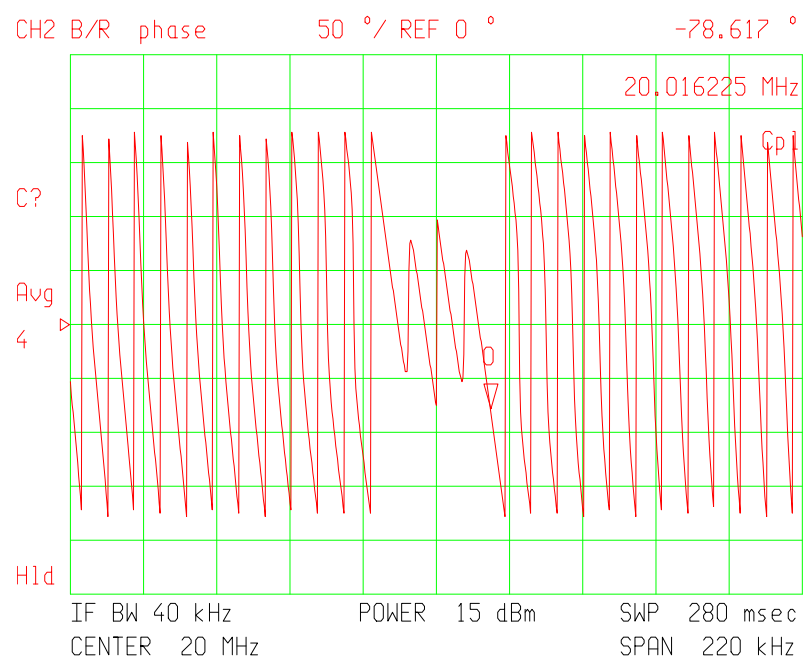
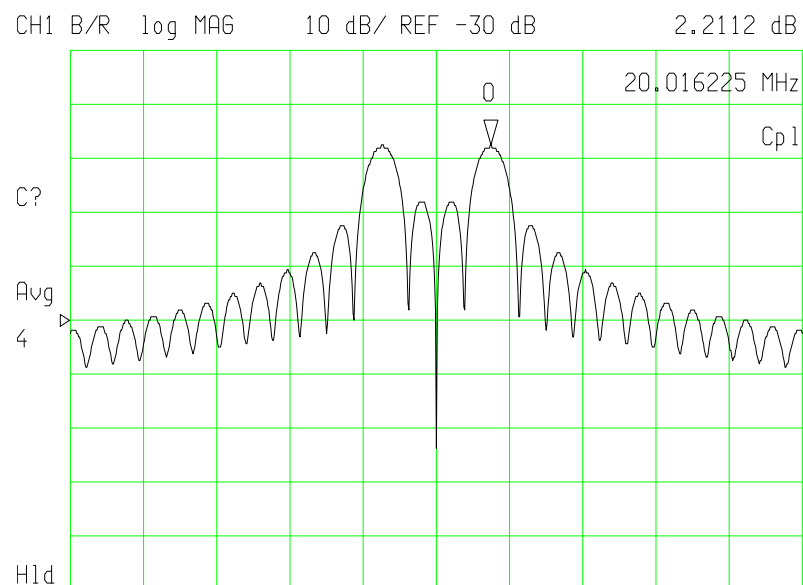


Figure 8: Filter, downsampling of 10